Power MOSFET

30 V, 51 A, Single N-Channel, SO-8 FL

Features

- Low R_{DS(on)} to Minimize Conduction Losses
- Low Capacitance to Minimize Driver Losses
- Optimized Gate Charge to Minimize Switching Losses
- NVMFS4C310NWF Wettable Flanks Option for Enhanced Optical Inspection
- AEC-Q101 Qualified and PPAP Capable
- These Devices are Pb-Free and are RoHS Compliant

MAXIMUM RATINGS (T_J = 25°C unless otherwise stated)

Parameter		Symbol	Value	Unit	
Drain-to-Source Voltage			V_{DSS}	30	V
Gate-to-Source Volta	age		V_{GS}	±20	V
Continuous Drain		T _A = 25°C		17	Α
Current R _{0JA} (Notes 1, 2 and 4)		T _A = 100°C	ID	12	
Power Dissipation $R_{\theta JA}$ (Notes 1, 2 and 4)	Stoody	T _A = 25°C	P _D	3.5	W
Continuous Drain Current R _{0.IC}	Steady State	T _C = 25°C		51	
(Notes 1, 2, 3 and 4)		T _C = 100°C	l _D	36	Α
Power Dissipation $R_{\theta JC}$ (Notes 1, 2, 3 and 4)		T _C = 25°C	P _D	32	W
Pulsed Drain Current	$T_A = 25^{\circ}C, t_p = 10 \mu s$		I _{DM}	132	Α
Operating Junction and Storage Temperature		T _J , T _{STG}	-55 to +175	°C	
Source Current (Body Diode)		I _S	21	Α	
Single Pulse Drain-to-Source Avalanche Energy (I _L = 25 A _{pk}) (Note 3)		E _{AS}	31	mJ	
Lead Temperature for Soldering Purposes (1/8" from case for 10 s)		T _L	260	°C	

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

- The entire application environment impacts the thermal resistance values shown, they are not constants and are only valid for the particular conditions noted.
- 2. Surface–mounted on FR4 board using 650 mm², 2 oz Cu pad.
- Assumes heat-sink sufficiently large to maintain constant case temperature independent of device power.
- 4. Continuous DC current rating. Maximum current for pulses as long as one second is higher but dependent on pulse duration and duty cycle.

THERMAL RESISTANCE MAXIMUM RATINGS

Parameter	Symbol	Value	Unit
Junction-to-Case (Drain)	$R_{ heta JC}$	4.7	
Junction-to-Ambient - Steady State (Note 5)	$R_{ hetaJA}$	43	°C/W

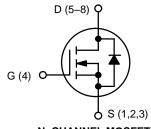
5. Surface-mounted on FR4 board using 650 mm², 2 oz Cu pad.



ON Semiconductor®

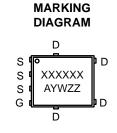
www.onsemi.com

V _{(BR)DSS}	R _{DS(ON)} MAX	I _D MAX
30 V	$6.0~\text{m}\Omega$ @ $10~\text{V}$	51 A
30 V	9.0 mΩ @ 4.5 V	SIA



N-CHANNEL MOSFET





4C10N = Specific Device Code for NVMFS4C310N 4C10WF= Specific Device Code of NVMFS4C310NWF

A = Assembly Location
Y = Year
W = Work Week
ZZ = Lot Traceability

ORDERING INFORMATION

Device	Package	Shipping [†]
NVMFS4C310NT1G	SO-8 FL (Pb-Free)	1500 / Tape & Reel
NVMFS4C310NWFT1G	SO-8 FL (Pb-Free)	1500 / Tape & Reel

†For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

ELECTRICAL CHARACTERISTICS (T_J = 25°C unless otherwise specified)

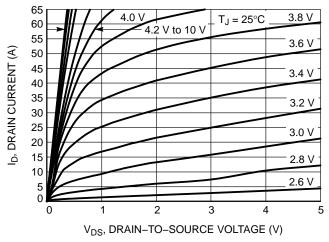
Parameter	Symbol	Test Condition		Min	Тур	Max	Unit	
OFF CHARACTERISTICS	•			•			•	
Drain-to-Source Breakdown Voltage	V _{(BR)DSS}	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		30			V	
Drain-to-Source Breakdown Voltage Temperature Coefficient	V _{(BR)DSS} / T _J				14.5		mV/°C	
Zero Gate Voltage Drain Current	I _{DSS}	V _{GS} = 0 V,	T _J = 25°C			1.0	- μΑ	
		V _{DS} = 24 V	T _J = 125°C			10		
Gate-to-Source Leakage Current	I _{GSS}	V _{DS} = 0 V, V _{GS} = 20 V				100	nA	
ON CHARACTERISTICS (Note 6)								
Gate Threshold Voltage	V _{GS(TH)}	$V_{GS} = V_{DS}, I_D$	= 250 μΑ	1.3		2.2	V	
Negative Threshold Temperature Coefficient	V _{GS(TH)} /T _J				4.7		mV/°C	
Drain-to-Source On Resistance	R _{DS(on)}	V _{GS} = 10 V	I _D = 30 A		5.0	6.0	1	
		V _{GS} = 4.5 V	I _D = 30 A		7.5	9.0	mΩ	
Forward Transconductance	9FS	V _{DS} = 1.5 V, I _E	_O = 15 A		43		S	
CHARGES AND CAPACITANCES								
Input Capacitance	C _{ISS}	V _{GS} = 0 V, f = 1 MHz, V _{DS} = 15 V			1000		pF	
Output Capacitance	C _{OSS}				580			
Reverse Transfer Capacitance	C _{RSS}				160			
Total Gate Charge	Q _{G(TOT)}	$V_{GS} = 4.5 \text{ V}, V_{DS} = 15 \text{ V}; I_D = 30 \text{ A}$			9.7		nC	
Threshold Gate Charge	Q _{G(TH)}				1.5			
Gate-to-Source Charge	Q_GS				2.8			
Gate-to-Drain Charge	Q_{GD}				4.8			
Gate Plateau Voltage	V_{GP}				3.2		V	
Total Gate Charge	Q _{G(TOT)}	V _{GS} = 10 V, V _{DS} = 15 V; I _D = 30 A			18.6		nC	
SWITCHING CHARACTERISTICS (Note 7)							•	
Turn-On Delay Time	t _{d(ON)}				9.0			
Rise Time	t _r	$V_{GS} = 4.5 \text{ V}, V_{DS} = 15 \text{ V},$ $I_{D} = 15 \text{ A}, R_{G} = 3.0 \Omega$			34		1	
Turn-Off Delay Time	t _{d(OFF)}	$I_D = 15 \text{ A, R}_G$	= 3.0 Ω		14		ns	
Fall Time	t _f				7.0		1	
Turn-On Delay Time	t _{d(ON)}	V_{GS} = 10 V, V_{DS} = 15 V, I_{D} = 15 A, R_{G} = 3.0 Ω			7.0			
Rise Time	t _r				26		1	
Turn-Off Delay Time	t _{d(OFF)}				18		ns	
Fall Time	t _f				4.0		1	
DRAIN-SOURCE DIODE CHARACTERISTIC	s						•	
Forward Diode Voltage	V _{SD}	V _{GS} = 0 V,	T _J = 25°C		0.80	1.1	V	
		I _S = 10 A	T _J = 125°C		0.67			
Reverse Recovery Time	t _{RR}	$V_{GS} = 0 \text{ V, } dI_{S}/dt = 100 \text{ A/}\mu\text{s,}$ $I_{S} = 30 \text{ A}$			26.7			
Charge Time	t _a				14.1		ns	
Discharge Time	t _b				12.6		1	
Reverse Recovery Charge	Q _{RR}				13.7		nC	

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

6. Pulse Test: pulse width ≤ 300 μs, duty cycle ≤ 2%.

7. Switching characteristics are independent of operating junction temperatures.

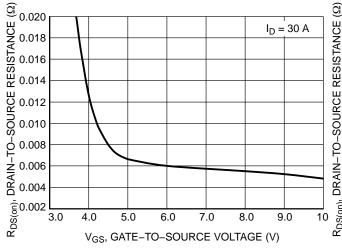
TYPICAL CHARACTERISTICS



80 $V_{DS} = 5 V$ 70 ID, DRAIN CURRENT (A) 60 50 40 30 $T_J = 125^{\circ}C$ 20 $T_J = 25^{\circ}C$ 10 $\Gamma_{\rm J} = -55^{\circ}$ C 0 0.5 1.5 2.0 2.5 3.0 3.5 4.0 1.0 V_{GS}, GATE-TO-SOURCE VOLTAGE (V)

Figure 1. On-Region Characteristics

Figure 2. Transfer Characteristics



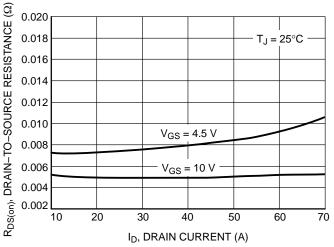
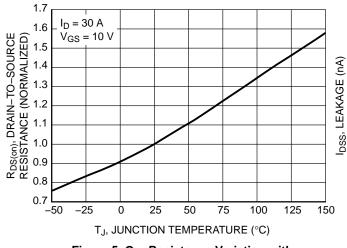


Figure 3. On-Resistance vs. V_{GS}

Figure 4. On–Resistance vs. Drain Current and Gate Voltage



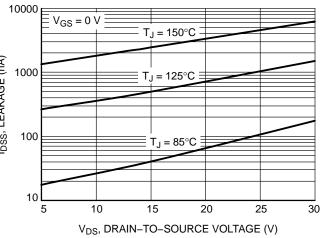


Figure 5. On–Resistance Variation with Temperature

Figure 6. Drain-to-Source Leakage Current vs. Voltage

TYPICAL CHARACTERISTICS

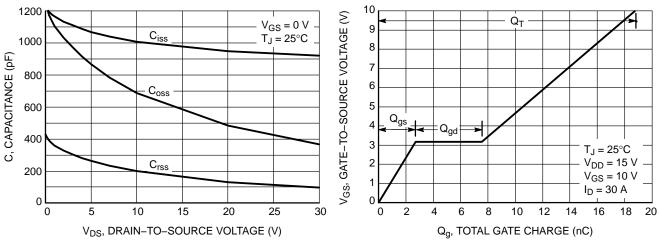


Figure 7. Capacitance Variation

Figure 8. Gate-to-Source and Drain-to-Source Voltage vs. Total Charge

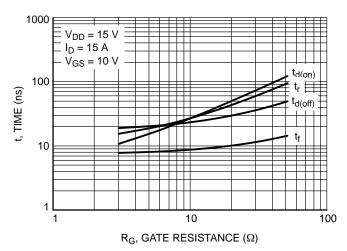


Figure 9. Resistive Switching Time Variation vs. Gate Resistance

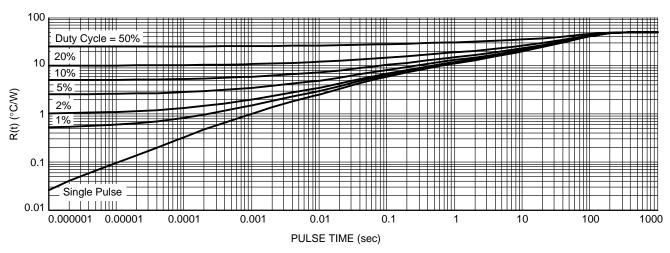


Figure 10. Thermal Response



0.10

0.10

SIDE VIEW

DFN5 5x6, 1.27P (SO-8FL) CASE 488AA ISSUE N

DATE 25 JUN 2018

NOTES:

BURRS

- DIMENSIONING AND TOLERANCING PER
- ASME Y14.5M, 1994.
 CONTROLLING DIMENSION: MILLIMETER.
 DIMENSION D1 AND E1 DO NOT INCLUDE MOLD FLASH PROTRUSIONS OR GATE

	MILLIMETERS			
DIM	MIN	NOM	MAX	
Α	0.90	1.00	1.10	
A1	0.00		0.05	
b	0.33	0.41	0.51	
С	0.23	0.28	0.33	
D	5.00	5.15	5.30	
D1	4.70	4.90	5.10	
D2	3.80	4.00	4.20	
E	6.00	6.15	6.30	
E1	5.70	5.90	6.10	
E2	3.45	3.65	3.85	
е	1.27 BSC			
G	0.51	0.575	0.71	
K	1.20	1.35	1.50	
L	0.51	0.575	0.71	
L1	0.125 REF			
M	3.00	3.40	3.80	
A	0 0		12 °	

GENERIC MARKING DIAGRAM*



XXXXXX = Specific Device Code

= Assembly Location Α

Υ = Year W = Work Week ZZ = Lot Traceability

*This information is generic. Please refer to device data sheet for actual part marking. Pb-Free indicator, "G" or microdot " ■", may or may not be present. Some products may not follow the Generic Marking.





DETAIL A

*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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